Freeform Search

Database:	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins		
Term:	L6 and lot number		
Display:	Documents in <u>Display Format</u> : - Starting with Number	1	
Generate:	C Hit List Hit Count C Side by Side C Image		
·	Search Clear Interrupt		**********
	Search History	r atalara (atalara lahatahanahanahanahanaha	to renerate le renerata totto ne
DATE: Monday	, August 16, 2004 Printable Copy Create Case		
Set Name Query side by side		<u>Hit</u> Count	Set Nam resul set
·	PT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		.
$\underline{L7}$ L6 and lot		25	1.7
L6 L2 and hist		93	<u>L6</u>
<u>l.5</u> ("5256578"	" "5761064" "5838951" "6016562" "6477685" "6559662" "6567168").PN.	19	<u>(i., j</u>

END OF SEARCH HISTORY

wafer defect

<u>L2</u>

L3 L2 and inspection parameter

hollington and wafer defect

For 10/604685

<u>L.4</u> ("6524881"|"6559457"|"20030003688A1").PN.

4 <u>I.4</u>

42 <u>L3</u>

1 <u>L1</u>

1384 <u>L2</u>